


<b>Search Notes</b>  	<b>Application/Control No.</b>  10058732	<b>Applicant(s)/Patent Under Reexamination</b>  IMAI ET AL.
	<b>Examiner</b>  LENA NAJARIAN	<b>Art Unit</b>  3626

SEARCHED			
Class	Subclass	Date	Examiner
705	2, 3	3/19/08	LN
705	2, 3	3/20/08	LN

SEARCH NOTES		
Search Notes	Date	Examiner
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	3/18/08	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	3/19/08	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	3/20/08	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/28/08	LN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner